

<b>Notice of References Cited</b>	Application/Control No. 10/714,397		Applicant(s)/Patent Under Reexamination LEE ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0047414 A1	11-2001	Yoon et al.	709/225
*	B	US-2002/0035624 A1	03-2002	Kim, Jun-hyeong	709/222
*	C	US-2002/0165972 A1	11-2002	Chien et al.	709/229
*	D	US-2003/0033418 A1	02-2003	Young et al.	709/230
*	E	US-2003/0093563 A1	05-2003	Young et al.	709/245
*	F	US-6,772,210 B1	08-2004	Edholm, Philip K.	709/226
*	G	US-2008/0279178 A1	11-2008	Chou et al.	370/352
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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